

FlexiHash™ For Battery Authentication

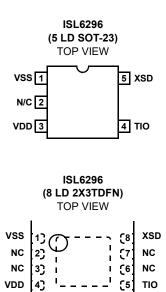
The ISL6296 is a highly cost-effective fixed-secret hash engine based on Intersil's FlexiHash™ technology. The device authentication is achieved through a challengeresponse scheme customized for low-cost applications, where cloning via eavesdropping without knowledge of the device's secret code is not economically viable. When used for its intended applications, the ISL6296 offers the same level of effectiveness as other significantly more expensive high maintenance monetary-grade hash algorithm and authentication schemes.

The ISL6296 has a wide operating voltage range, and is suitable for direct powering from a 1-cell Li-lon/Li-Poly or a 3-cell series NiMH battery pack. The ISL6296 can also be powered by the XSD bus when the bus pull-up voltage is 3.3V or higher. The device connects directly to the cell terminals of a battery pack, and includes on-chip voltage regulation circuit, POR, and a non-crystal based oscillator for bus timing reference.

Communication with the host is achieved through a singlewire XSD interface - a light-weight subset of Intersil's ISD bus interface. The XSD bus is compatible for use with serial ports offered by all 8250 compatible UART's or a single GPIO (general purpose input and output) pin of a microprocessor.

A clone prevention solution utilizing the ISL6296 offers safety and revenue protection at the lowest cost and power, and is suitable for protection against after-market replacement for a wide variety of low-cost applications.

Pinouts



Features

- Challenge-response based authentication scheme using 32-Bit challenge code and 8-Bit authentication code.
- · Fast and flexible authentication process. Multi-pass authentication can be used to achieve the highest security level if necessary.
- 16x8 OTP ROM stores up to three sets of 32-Bit hostselectable secrets with additional programmable memory for storage of up to 48 bits of ID code and/or pack information.
- FlexiHash engine uses two sets of 32-Bit secrets for authentication code generation.
- Non-unique mapping of the secret key to an 8-Bit authentication code manifizes hacking difficulty due to need for exhaustive key search (superior to SHA-1).
- · Supports 1-cell Li-Ion/Li-Poly and 3-cell series NiMH battery packs (2.6V ~ 4.8V operation), or powered by the XSD bus.
- · XSD single-wire host bus interface communicates with all 8250-compatible UART's or a single GPIO. Supports CRC on read data and transfer bit-rate up to 23kbps.
- · True "Zero Power" Sleep mode automatically entered after a bus inactivity time-out period
- 5 Ld SOT-23 and 8 Ld TDFN (2mm x 3mm) packages
- -20°C to +85°C operating temperature range
- · Pb-free plus anneal available (RoHS compliant)

Applications

- Battery Pack Authentication
- Printer Cartridges
- Add-on Accessories
- Other Non-Monetary Authentication Applications

Related Literature

- Application Note AN1165 "ISL6296 Evaluation Kit"
- Application Note AN1166 "FlexiHash™ Engine Algorithm"
- Application Note AN1167 "Implementing XSD Host Using a GPIO"
- Technical Brief TB363 "Guidelines for Handling and Processing Moisture Sensitive Surface Mount Devices (SMDs)



Ordering Information

PART NUMBER (Note)	PART MARKING	TEMP. RANGE (°C)	E PACKAGE (Pb-free) D	
ISL6296DHZ-T	296Z	-20 to +85	5 Ld SOT-23 Tape and Reel	P5.064
ISL6296DRZ-T	96Z	-20 to +85 8 Ld 2x3 TDFN Tape and Reel L8.		L8.2X3A
ISL6296EVAL1	ISL6296 Evaluation Kit			

NOTE: Intersil Pb-free plus anneal products employ special Pb-free material sets; molding compounds/die attach materials and 100% matte tin plate termination finish, which are RoHS compliant and compatible with both SnPb and Pb-free soldering operations. Intersil Pb-free products are MSL classified at Pb-free peak reflow temperatures that meet or exceed the Pb-free requirements of IPC/JEDEC J STD-020.



Absolute Maximum Ratings (Reference to GND)

Supply Voltage (VDD) 5.5V All Other Pins -0.5 to VDD+0.5V
ESD Rating
Human Body Model (Per MIL-STD-883 Method 3015.7)4000V
Machine Model (Per EIAJ ED-4701 Method C-111)
CDM
Recommended Operating Conditions

Ambient Temperature Range-20°C to +85°C

Thermal Information

Thermal Resistance (Typical)	θ _{JA} (°C/W)	$\theta_{\rm JC}$ (\Box , \bullet , \bullet ,
SOT-23 Package (Note 1)	200	N/A
2x3 TDFN Package (Notes 2, 3)	70	10.5
Mar mum Junction Temperature (Plastic P	Package)	+125°C
Mar mum Storage Temperature Range	4 0°	°C to +125°C
Mar mum Lead Temperature (Soldering 10	0s)	+300°C

CAUTION: Stresses above those listed in "Absolute national matings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

- 1. θ_{JA} is measured with the component mounted on a high effective thermal conductivity test board in the alr. See Tech Brief TB379 for details.
- 2. θ_{JA} is measured in **thee all w**ith the component mounted on a high effective thermal conductivity test board with "direct attach" features. See Tech Brief TB379.
- 3. For θ_{IC} , the "case temp" location is the center of the exposed metal pad on the package underside.

Electrical Specifications Unless otherwise noted, all parameters are guaranteed over the operational supply voltage and temperature range of the device as follows: $T_A = -20^{\circ}$ C to $+85^{\circ}$ C; $V_{DD} = 2.6$ V to 4.8V.

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	ТҮР	MAX	UNITS
DC CHARACTERISTICS						
Supply Voltage	V _{DD}	During normal operation	2.6	-	4.8	V
		During OTP ROM programming	2.8	-	4.8	V
Run Mode Supply Current	I _{DD}	V _{DD} = 4.2V	-	110	140	μA
(exclude I/O current)		V _{DD} = 4.8V	-	120	160	μA
Sleep Mode Supply Current	I _{DDS}	V _{DD} = 4.2V, XSD pin floating	-	0.15	0.5	μA
OTP Programming Mode Supply Current	I _{DDP}	For ~ 1.8ms duration per write operation	-	250	500	μA
Internal Regulated Supply Voltage	V _{RG}	Observable only in test mode	2.3	2.5	2.7	V
Internal OTP ROM Programming Voltage	V _{PP}	Observable only in test mode	11	12	13	V
POR Release Threshold	V _{POR+}		1.9	2.2	2.4	V
POR Assertion Threshold	V _{POR-}		1.5	1.8	2.1	V
XSD PIN CHARACTERISTICS						
XSD Input Low Voltage	VIL		-0.4	-	0.5	V
XSD Input High Voltage	VIH		1.5	-	V _{DD} + 0.4V	V
XSD Input Hysteresis	V _{HYS}		-	400	-	mV
XSD Internal Pull-Down Current	I _{PD}	V _{DD} = 2.6V	-	0.8	-	μA
		V _{DD} = 4.2V	-	1.2	2.0	μA
		V _{DD} = 4.8V	-	1.8	2.5	μA
XSD Output Low Voltage	V _{OL}	I _{OL} = 1mA	-	-	0.4	V
XSD Input Transition Time	t _X	10% to 90% transition time	-	-	2	μs
XSD Output Fall Time	t _F	90% to 10%, C _{LOAD} = 12pF	-	-	50	ns
XSD Pin Capacitance	C _{PIN}		-	6	-	pF
XSD BUS TIMING CHARACTERISTICS	(Refer to X	SD Bus Symbol Timing Definitions Tables)				
Programming Bit Rate		x = 0.5 to 4	2.89	-	23.12	kHz
XSD Input Deglitch Time	T _{WDG}	Pulse width narrower than the deglitch time will not cause the device to wake up	7	-	20	μs

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Electrical Specifications Unless otherwise noted, all parameters are guaranteed over the operational supply voltage and temperange of the device as follows: $T_A = -20^{\circ}$ C to $+85^{\circ}$ C; $V_{DD} = 2.6$ V to 4.8V. (Contractional supply voltage and temperange)

ſ	ange of the devi	ce as follows: $T_A = -20$ C to +85 C; $V_{DD} = 2.6V$ to 4.8V.	(Comin	U9 (I)		Onin
PARAMETER	PARAMETER SYMBOL TEST CONDITIONS		MIN	TYP	MAX	UNITS
Device Wake-Up Time	T _{WKE}	From falling-edge of break command issued by host to falling-edge of break command returned by device	35	60	100	μs
Device Sleep Wait Time	T _{SLP}	From when the '11' Opcode is detected to the shut-off of the internal regulator	4	-	-	μs
Auto-Sleep Time-Out Period	T _{ASLP}	From the last transition detected on the XSD bus to the device going into sleep mode	0.9	-	1.1	S
OTP ROM Write Time	T _{EEW}	From the last BT of the 2nd write data frame to when device is ready to accept the next instruction	-	1.8	1.9	ms
Hash Calculation Time	T _{HASH}	From the last BT of the Challenge Code Word from the host to the Authentication Code being available for read	-	1	-	BT
Soft-Reset Time	T _{SRST}	From the last BT of the Soft-Reset instruction issued by the host to the falling-edge of break command returned by device	-	-	30	μs
AC CHARACTERISTICS	¥					
Oscillator Clock Frequency	fosc	Internal bus reference clock	505	532	560	kHz
Charge Pump Clock Frequency	f _{CP}	Internal high speed clock (observable only in test mode)				
		Low-speed mode	3.6	5	6	MHz
		High-speed mode	16	20	24	MHz

Pin Descriptions

PIN NUMBER	PIN NAME	DESCRIPTION		
1	VSS	System ground.		
2	NC	No connection.		
3	VDD	Supply voltage.		
4	TIO	Production test I/O pin. Used only during production testing. Must be left floating during normal operation.		
5	XSD	Communication bus with weak internal pull-down to VSS. This pin is a Schmitt-trigger input and an open-drain output. An appropriate pull-up resistor is required on the host side.		



Typical Applications

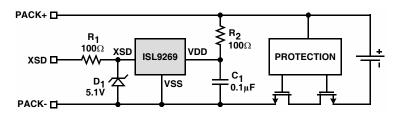


FIGURE 1. TYPICAL APPLICATION WITH THE ISL6296 POWERED BY THE BATTERY

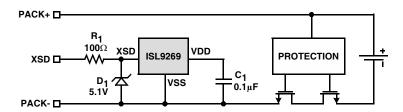
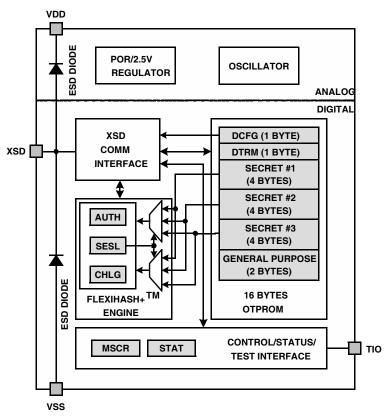


FIGURE 2. TYPICAL APPLICATION WITH THE ISL6296 POWERED BY THE XSD BUS

Block Diagram





Theory of Operation

The ISL6296 contains all circuitry required to support battery pack authentication based on a challenge-response scheme. It provides a 16-Byte One-Time Programmable Read-Only Memory (OTPROM) space for the storage of up to 96-Bit of secret for the authentication and other user information. A 32-Bit CRC-based hash engine (FlexiHash[™]) calculates the authentication result immediately after receiving a 32-Bit random challenge code. The communication between the ISL6296 and the host is implemented through the XSD single-wire communication bus.

Major functions within the ISL6296 include the following, as shown in Figure 3.

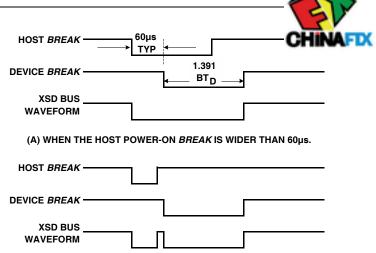
- Power-on reset (POR) and a 2.5V regulator to power all internal logic circuits.
- 16 x 8-Bit (16-Byte) OTP ROM as shown in Table 8. The first part (two bytes) contains the device default configuration (DCFG) information (such as the device address and the XSD communication speed) and the default trimming (DTRM) information (such as the internal oscillator frequency trimming). The second part contains two groups (12-Byte) of memory that can be independently locked out for the storage of up to three sets of secret. The last part provides two additional bytes of space for general-purpose information.
- Control functions, including master control (MSCR) and status (STAT) registers (as shown in Table 9), interrupt generation, and the test-related interface.
- FlexiHash[™] engine that includes the 32-Bit CRC-based hash engine, secret selection register, challenge code register, and the authentication result register. Table 10 shows all the registers.
- XSD communication bus Interface. The XSD device address and the communication speed are configured in the DCFG address in the OTPROM, as given in Table 8.
- Time Base Reference.

The following explain in detail the operation of the ISL6296.

Power-On Reset (POR)

The ISL6296 powers up in Sleep mode. It remains in Sleep mode until a power-on 'break' command is received from the host through the XSD bus. The initial power-on 'break' can be of any pulse width as long as it is wider than the XSD input deglitch time (20μ s). Once the 'break' command is received, the internal regulator is powered up. About 20μ s after the falling edge of the power-on 'break', an internal POR circuit releases the reset to the digital block, and a POR sequence is started. During the POR sequence, the ISL6296 initializes itself by loading the default device configuration information from pre-assigned locations within the OTP ROM memory. After initialization, a 'break' command is returned to the host to indicate that the ISL6296 is ready and waiting for a bus transaction from the host.

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(B) WHEN THE HOST POWER-ON BREAK IS NARROWER THAN 60µs.

FIGURE 4. POWER-ON BREAK SIGNAL TO WAKE-UP THE ISL6296 FROM SLEEP MODE

Note that the ISL6296 will initiate the power-on sequence without waiting for the power-on 'break' signal to return to the high state. If the host sends an initial 'break' pulse wider than 60μ s, the device-ready 'break' returned by the ISL6296 will likely be merged with the pulse sent by the host and, therefore, may not be detectable. Figure 4 illustrates the waveforms during the Power-on Reset. Figure 4 (A) represents the case when the power-on 'break'. Figure 4 (B) represents the case when the power-on 'break'. Figure 4 (B) represents the case when the power-on 'break'. Figure 4 (B) represents the case when the power-on 'break'. Figure 4 (B) represents the case when the power-on 'break'. Figure 4 (B) represents the case when the power-on 'break' finishes before the device sends its 'break'. The device break signal is always 1.391 times of the device bit-time (BT, see XSD Bus Interface section for more details). Either case in Figure 4 will wake up the device successfully if the device is in the sleep mode.

It is important to keep in mind that a narrow 'break' signal will be taken as a normal bit signal and cause errors, if the device is not in the sleep mode. For this reason, the narrow power-on 'break' signal should be used only if the user has to see the returned 'break' signal.

Auto-Sleep

While the ISL6296 is powered up and there is no bus activity for more than about 1 second, the device will automatically return to Sleep mode. Sleep mode can be entered independent of whether the XSD bus is held high or low. While the ISL6296 is in Sleep mode, it is recommended that the XSD bus be held low to eliminate current drain through the XSD-pin internal pull-down current.

Auto-Sleep mode can be disabled by clearing the ASLP bit in the MSCR register. By default, Auto-Sleep is always enabled at power-up and after a soft reset. Auto-sleep function can be permanently disabled by clearing the 0-00[2] bit (the ASLP bit in DCFG) during OTP ROM programming. 以上内容仅为本文档的试下载部分,为可阅读页数的一半内容。如 要下载或阅读全文,请访问: <u>https://d.book118.com/31500234220</u> <u>1011234</u>